



PATENT Customer No. 22,852 Attorney Docket No. 3180.0342

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)
NOBUHIRO KOMINE	) )
Application No.: 10/721,903	) Group Art Unit: 2851
Filed: November 26, 2003	) Examiner: D. Rutledge
For: RETICLE, EXPOSURE MONITORING METHOD, EXPOSURE METHOD AND MANUFACTURING METHOD FOR SEMICONDUCTOR DEVICE	) ) Confirmation No.: 9102 ) ) ) )

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

## INFORMATION DISCLOSURE STATEMENT UNDER 37\_C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§ 1.56 and 1.97(b), applicant brings to the attention of the Examiner the documents on the attached listing. This Information Disclosure Statement is being filed concurrently with a Request for Continued Examination Transmittal in the above-referenced application.

Copies of the listed foreign and non-patent literature documents are attached.

Applicant respectfully requests that the Examiner consider the listed documents and indicate that they were considered by making appropriate notations on the attached form.

In lieu of a statement of relevance or translation of the non-English documents, enclosed is a Notice of Grounds for Rejection issued by the Japanese Patent Office in a counterpart Japanese application, mailed June 21, 2005, citing these documents and setting forth the relevance thereof. In addition, an English-language translation of the Notice is attached. Further, Applicant notes that Japanese Patent Laid-Open No. 2000-310850 is discussed on pages 2-3 of the present specification.

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claim in the application and applicant determines that the cited documents do not constitute "prior art" under United States law, applicant reserves the right to present to the office the relevant facts and law regarding the appropriate status of such documents.

Applicant further reserves the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated: X 10

Bv:

Richard V Burquiid

Reg. No. 31,7

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## INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

Sheet 1 of

· •	Complete if Known	PE
Application Number	10/721,903	· e
Filing Date	November 26, 2003	1 0 3000
First Named Inventor	Nobuhiro Komine	VAB ,
Art Unit	2851	12
Examiner Name	D. Rutledge	Te more
Attorney Docket Numbe	r 3180.0342	THAT

	U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner	Cite	Document Number	Dublication Data	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where	
Initials	No.'	Number-Kind Code <sup>2</sup> (if known)			Relevant Passages or Relevant Figures Appear	
		US-				
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Note: Submission of copies of U.S. Patents and published U.S. Patent Applications is not required.

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. <sup>1</sup>	Foreign Patent Document  Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>6</sup>
		JP 2001-319871	11/16/01	Nikon Corp.		Abstract
		JP 2000-310850	11/7/00	Toshiba Corp.		Abstract
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•	NON PATENT LITERATURE DOCUMENTS				
Examiner Cite Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the iter (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.		Translation <sup>6</sup>			
		Notice of Grounds for Rejection, issued by the Japanese Patent Office, mailed June 21, 2005, in Japanese Patent Application Serial No. P2002-342798, and English-language translation thereof			
		DIRKSEN et al., "Focus and exposure dose determination using stepper alignment," SPIE (1996), 2726:799-808			
		STARIKOV, "Exposure Monitor Structure," SPIE (1990), 1261:315-324			

Examiner Signature	Date Considered	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.